

*“Element Specific Atom Counting at the Atomic Scale by Combining High Angle Annular Dark Field Scanning Transmission Electron Microscopy and Energy Dispersive X-ray Spectroscopy”*. De Backer A, Zhang Z, van den Bos KHW, Bladt E, Sánchez-Iglesias A, Liz-Marzán LM, Nellist PD, Bals S, Van Aert S, Small methods , 2200875 (2022). <http://doi.org/10.1002/smt.202200875>